

622 Mb/s Optical Line Interface

Agilent Technologies Broadband Series Test System

E1618A



The Agilent E1618A 622 Mb/s Optical Line Interface (LIF) is a single slot, single port (1 Tx/1 Rx) VXI module for the BSTS that provides access to OC-12c/STM-4c devices.

The Agilent Technologies E1618A 622 Mb/s Optical Line Interface provides OC-12c (SONET STS-12c and SDH STM-4c) access to the system under test via SC optical connectors. The LIF is a singe-mode device that can also be used with multi-mode systems when the appropriate attenuator is fitted.

Functionality includes alarm and error generation and detection, as well as extensive testing of line, section, and path overheads.

Payload pointer testing includes pointer stressing and measurement of both loss of pointer synchronization and pointer values. Section and path trace messages can be generated and captured in 16 and 64 byte formats.

External triggers can be used to synchronize transmitter or receiver events to other test equipment or network devices.

Product Features

- Full-rate 622 Mb/s SONET/SDH generation and analysis
- SONET/SDH transport overhead building, generation, error injection, capture, and save/load
- Alarm generation and detection
- BIP error injection and detection
- Payload pointer stressing
- Trace message generation & capture
- Automatic REI alarm generation
- Graphing and logging of real-time statistics for correlation of multiple measurements
- Tcl and C-scripting automated test environment (UPE)
- Optical and Electrical 622 Mb/s interfaces
- Works with the E1609A 0-622 Mb/s ATM Stream Processor for 2-slot full rate 622 Mb/s ATM traffic testing
- Access to the Agilent E4209B Cell Protocol Processor for signalling and higher layer test (directly or via the Agilent E1609A)

All user documentation is provided online, in a web-based format that can be accessed and searched using a web browser.

You can connect the Agilent E1618A LIF directly to the Agilent E4209B Cell Protocol Processor (CPP) for a cost effective signalling test solution at 622 Mb/s.



Key Features

SONET/SDH Transport Overhead

Create and generate line, section, and path overheads, set invalid values and inject errors to test the limits of system and network performance. You can save the overhead bytes that you build to disk, and reload them to repeat your tests.

Received line, section, and path overheads are displayed and updated once every second. You can take a snapshot and save the captured overhead bytes to disk for further analysis.

Alarms, Errors, and Correlation of Statistics

You can generate SONET/SDH alarms and inject errors to test fault recovery performance and check that your network operation is robust. Bit errors can be simulated by inverting the section, line, and path (B1/B2/B3) bytes.

To help you find and analyze faults, alarms are monitored, and common alarms and indications such as LOF (loss of frame) are also displayed on the front panel using LEDs.

Transmission performance can be quantified by counting BIP errors and other metrics, such as the number of seconds of alarm condition occurring during the measurement period.

Real-time statistics, such as received 8 kHz frame count or SPE count, can be measured and logged to disk. These measurements can be reported as errored seconds, event counts, or as error ratios.

Multiple statistics can be graphed simultaneously and updated in real-time, allowing you to correlate statistics to help find the reason for a fault or performance degradation.

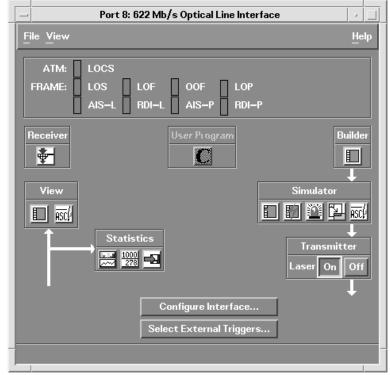


Figure 1: The main control panel for the E1618A.

Payload Pointer

Payload pointer testing includes:

- pointer movement generation
- pointer stressing using invalid values
- detection and measurement of loss of pointer synchronization (LOP)
- real-time measurement of both transmit and receive pointer values

Trace Messages

To help you trace a service or a fault through your network, section and path trace messages can be built and generated in both 16 and 64 byte formats. You can also capture trace messages and view them in either format.

ATM

When ATM cells are generated or received through the line interface, SONET/SDH frame scrambling and descrambling can be enabled or disabled, and single-bit ATM header error correction can be selected.

ATM real-time measurements, such as Bad Header counts and Loss of Cell Synchronization seconds, can be graphed and correlated with physical layer statistics.

User Programming Environment

An Application Programming Interface (API) is provided to enable you with the tools to develop regression tests and automated test suites. Test programs can be built in the industry-standard environment of "C" and Unix. For remote system testing, scripts and user interfaces can be rapidly developed in Tcl/Tk.

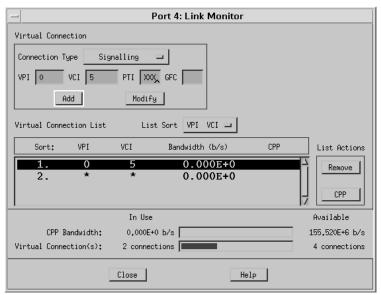


Figure 2: The link monitor of the E1618A 622 Mb/s Optical Line Interface which can be used to pass up to 6 channels to the CPP (E4209B).

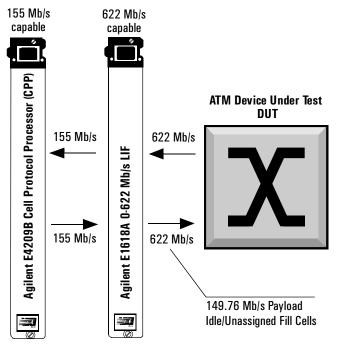


Figure 3: Passing cells to and from the Agilent E1618A 622 Mb/s LIF to the Agilent E4209B CPP.

Higher Layer Analysis

The E1618A LIF shares the BSTS 155 Mb/s cell bus. Modules like the Agilent E4209B CPP, Agilent E4219A ATM Network Impairment Module, and Agilent E6270A OAM Protocol Tester are capable of 149.76 Mb/s generation, impairment and analysis.

The Agilent E4209B CPP can be used to generate up to 149.76 Mb/s of user-defined traffic via the 155 Mb/s BSTS cell bus both in and out of the E1618A 622 Mb/s LIF. Likewise, when receiving full-rate 599.04 Mb/s ATM traffic, you can specify up to 6 channels that can be passed to the E4209B CPP via the Link Monitor (as shown in figure 2) as long as the sum of the bandwidth does not exceed 149.76 Mb/s.

Web-Based Online Documentation

Learning to make the most of an analyzer has never been easier, thanks to the web-based online documentation and context-sensitive help. Occasional users will benefit from the ability to browse and search for a particular feature, and the ability to bookmark a useful reference page. Frequent users are already linking their test plans with protocol specifications and with our task-based help to bring their products and services to market more rapidly.

Configuration and Use With Other BSTS Modules and Applications

Testing OC-12c/STM-4c devices completely and rigorously is why the Agilent BSTS is so popular with equipment manufacturers and service providers worldwide.

In addition to the Agilent E1618A, there is a suite of products available on the BSTS that tailored for your test requirements. The following BSTS products can be used in conjunction with the E1618A:

- Agilent E1609A 0-622 Mb/s ATM Stream Processor - for full-rate 622 Mb/s traffic generation and analysis
- Agilent E4209B Cell Protocol Processor (CPP) - to enable SVC-based test scenarios at OC-12c/STM-4c
- Agilent E6270A OAM Protocol Tester - to provide up to 155 Mb/s OAM PM/RM analysis over an OC-12c/STM-4c link
- E4219A ATM Network Impairment Emulator - to impair cell streams up to 149.76 Mb/s over an OC-12c/STM-4c link

The following software products running on the E4209B can also be used:

- Agilent E4214B UNI Signalling Test Software
- Agilent E4215B LAN Protocols Test Software
- Agilent E4217B NNI Signalling Test Software
- Agilent E4223A ATM Policing & Traffic Characterization Software
- Conformance test suites

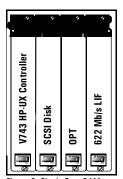


Figure 4: The Agilent E1609A ATM Stream Processor.

Agilent E1609A 0-622 Mb/s ATM Stream Processor

The Agilent E1609A is a product that takes the BSTS traffic generation and analysis capability to a higher level; removing the shortcomings of the CPP's traffic generation implementation. The Agilent E1609A provides:

- full-rate 622 Mb/s generation and analysis
- generation of ATM and AAL-5 user-defined payloads on up to 16,384 VCs.
- real-time ATM and AAL-5 statistics
- real-time, multi-channel ATM layer QoS
- shaped traffic generation on multiple streams



622 Mb/s LIF

Figure 5: Dual Port SVC Testing with full rate 622 M/s

Mb/s LIF

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ASP

V743 HP-UX Controller

SCSI

traffic generation.

CPP

Figure 6: Single Port OAM testing over an OC-12c/STM-4c link.

LIF	Agilent E1618A 622 Mb/s
	Line
	Interface
CPP	Agilent E4209B Cell Protocol
	Processor
ASP	Agilent E1609A 0-622 Mb/s
	ATM Stream Processor
OPT	Agilent E6270A OAM
	Protocol Tester

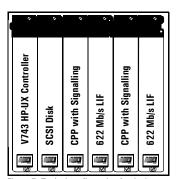


Figure 7: Typical configuration for dual port signalling testing over OC-12c/STM-4c.

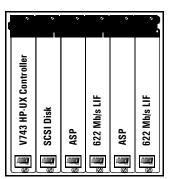


Figure 8: Dual Port PVC testing with full rate 622 Mb/s traffic generation.

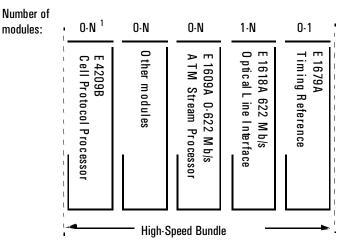


Figure 9: From E1609A ASP software release 1.1, multiple CPP modules can be used to monitor the same traffic received on the low-speed 155 Mb/s cell bus, and to generate and inject traffic onto the low-speed bus up to the bus bandwidth limit of 155 Mb/s (which represents an ATM cell bandwidth of 149.76 Mb/s).

Total Number of Consecutive Modules

The E1618A 622 Mb/s Optical Line Interface and E1609A 0-622 Mb/s ATM Stream Processor (ASP) modules communicate via a high-speed 622 Mb/s cell bus. Up to 3 consecutive modules can operate on the high-speed cell bus.

Traffic generated from the CPP and other modules on the low-speed bus takes precedence over traffic generated from the E1609A ASP. This enables signalling, higher-layer, and variable-rate traffic to be generated from the CPP while using the E1609A ASP to fill the remaining link bandwidth.

Figure 9 illustrates valid module configurations for the E1618A.

The "high-speed bundle" may be placed adjacent to additional high-speed bundles and to other modules, up to the limits of the chassis.

Your local Agilent field engineer will help you select the best test system configuration to meet your needs. Since the Agilent Broadband Series Test System is a flexible and modular ATM/B-ISDN test platform, you can maximize the return on your test equipment investment by selecting a chassis, line interfaces, dedicated hardware modules, and test software that suit your specific needs. Remember that you can always add extra software or modules at any time.

Adapters available for multimode and singlemode systems and connector alternatives

The singlemode E1618A 622 Mb/s Optical Line Interface has SC transmit and receive connectors hardmounted into the VXI card. The majority of OC-12c/STM-4c interfaces on switches today support singlemode transmission and terminate using SC connectors. However, there are some configurations that continue to use the FC/PC and ST type connectors and may also support multimode transmission.

Unlike other BSTS optical line interface cards, it is not possible to remove the optical connector and replace it with the desired type, instead, an adapter and/or attenuator is required. The following list describes the new kits available for the E1618A.

 E5137A SC Attenuator Kit Contains one SC 10dB attenuator for customers who need a multimode SC solution.

Warranty & Support Options

Hardware

All BSTS hardware components are warranted for a period of 3 years. Products must be returned to an authorized Agilent service center for service.

Software

Agilent Broadband Series Test System software and firmware products are supplied on transportable media such as disk, CD-ROM or integrated circuits. The warranty covers physical defects in the media, and defective media is replaced at no charge during the warranty period. When installed in an Agilent Broadband Series Test System, the software/firmware media has the same warranty period as the product.

Product Numbers

E1609A 0-622 Mb/s ATM

Stream Processor (ASP)

E1618A 622 Mb/s Optical

Line Interface (LIF) with SC

Connectors

Opt # UHV ST Connectors
Opt # UHW FC/PC Connectors
Opt # UK6 Calibration Certificate

E1537A

Opt # UHV ST Connectors Opt # UHW FC/PC Connectors

E4200B BSTS Form-7

Transportable Chassis

E4210B BSTS Form-13

Mainframe Chassis

E4209A/B Cell Protocol Processor

(CPP)

E5137A SC Multimode Attenuator

Ordering Information

E4200/E4210B #040

622 Mb/s Real-Time ATM Analyzer Bundle (E1609A, E1618A)

E4200/E4210B #140

622 Mb/s Real-Time ATM Protocol Test Bundle (E4209B, E1609A, E1618A)

E4200/E4210B #140

622 Mb/s Real-Time ATM Protocol Test Bundle (E4209B, E1609A, E1618A)

SONET/SDH Layer Specification

Formats

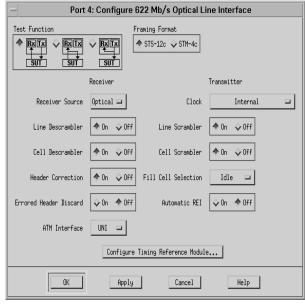
Framing Formats

SONET	 STS-12c as per ANSI T1.105 and Telcordia GR-253-CORE (Issue 1, Dec. 94)
SDH	• STM-4c as per ITU-T Re G.708/G.709, 1993
Scrambling	
SONET	 Frame synchronous scrambler as per ANSI T1.105 and Telcordia GR-253-CORE (Issue 1, Dec. 94)
SDH	 STM-4c as per ITU-T Rec G.708/G.709, 1993.

Overhead Data

SONET/SDH Overhead Generation

20ME 1/2Du Overliean gelietation		
J0/Z0	Offset 1 SONET & SDH: reserved for section trace as required; otherwise default value of 01H Offsets 2 – 4 SONET: incrementing pattern SDH: default value of 01H Offsets 5 – 12 SONET & SDH: user-definable	
B1, B2, B3	Automatically calculated	
M1/Z2	User-definable Line/MS REI value	
H1, H2, H3	Set SPE/AU4 pointer bytes to any fixed value as per Telcordia GR-253-CORE and ITU-T G.708/G.709 (with or without NDF)	
Pointer Movement	 Single increment/decrement NDF flag set operation Pointer value > 782 	
G1	User-definable Path RDI alarm using 3-bit format as per ANSI T1.105 and ITU-T G.708/G.709 User-definable Path REI value	
K1, K2	User-definable value (default 00H)	
Trace Operation	Section (J0) and path trace (J1) can be generated in both 16 and 64 byte formats	
Other Overhead Bytes	All programmable bytes will default to 00H All bytes can be programmed using the overhead viewer	



SONET/SDH Overhead Receiver Function

Trace Capture	 Section (J0) and path (J1) trace can be captured in both 16 and 64 byte formats
TOH Capture	 Single snap shot of line and section overhead bytes
POH Capture	Single snap shot of path overhead bytes
Link Control	
Network Interface	Select UNI or NNI
Fill Cells	Select idle (default) or unassigned.

Alarm Generation and Error Injection

Alarm Operating Modes (applies to all alarms)

Applicable Modes • Full duplex

• Transmit loopback (near end loopback)

SONET/SDH Alarm Generation

SONET Alarms	Control		
AIS-L	On/Off		
RDI-L	On/Off		
AIS-P	On/Off		
RDI-P	 On/Off; selectable defect type 		

SDH Alarms Control

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MS-AIS	On/Off
MS-RDI	On/Off
Path-AIS	On/Off
Path-RDI	 On/Off; selectable defect type
REI Error Injection	
ner error injudition	
REI-P	Single injection of REI-P value (1-8)
REI-L	Simple on/off with value 01-60H
Report	 REI-L and REI-P can be set based on receiver line and path BIPs
Frameword Error Inje	ection
A1	 Injection of 76H — first offset only — single-bit error
Error State	• On/Off
BIP Error Injection	
Section	On/Off BIP error injection by inverting B1 byte
Line	On/Off BIP error injection by inverting B2 bytes
Path	On/Off BIP error injection by inverting B3 byte

M	ea	su	re	m	e	nt	S
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Measurement System

Result Types	Cumulative: Measurements since the start of the measurement period Latched: Measurements during most recent completed measurement period
Result Formats	Count (C)Ratio (R)Seconds (S)
Accuracy of Counts	 < = 1% for counts < 1000 < = 0.1% for counts > = 1000
Accuracy of Ratios	• <=0.1% for counts >= 1000
Measurement Period	Range: 1 second to 3 days Resolution: 1 second

Measurements are sampled every 100 milliseconds and accumulated over the user-specified measurement period. Results from the most recent complete measurement period are retained.

SONET/SDH Real-Time Measurement

B1 Errors (C, R, S) • Section/RS-BIP errors detected

B2 Errors (C, R, S)	Line/MS-BIP errors detected
B3 Errors (C, R, S)	Path BIP errors detected
REI-L/MS-REI (C, R, S)	SONET: REI-L errors counted SDH: MS-REI errors counted
REI-P (C, R, S)	REI-P errors counted
LOS (S)	Loss of Signal
00F (S)	Out of Frame Based on condition of first A1 byte and first four bits of the first A2 byte in each frame
AIS-L/MS-AIS (S)	SONET: AIS-L condition detected SDH: MS-AIS condition detected
RDI-L/MS-RDI (S)	SONET: RDI-L condition detected SDH: MS-RDI condition detected
LOP (S)	Loss of Pointer synchronization
Tx Pointer	Current transmit pointer value
Rx Pointer	Current receive pointer value
AIS-P (S)	AIS-P condition detected
RDI-P (S)	RDI-P condition detected and defect decoded
Rx Frame Count (C)	Counts 8 kHz frames
Rx SPE Count (C)	Counts SPEs

ATM Layer Specification

ATM Characteristics

Transmit Functions

This module cannot generate ATM cells on its own — a companion module, such as the E1609A 0-622 Mb/s ATM Stream Processor, is required.

SONET/SDH framing is provided for ATM cells generated from other modules.

ATM Header	 Unmodified
ATM Payload	• Unmodified
Cell Scrambling	Select on/off
Receive Functions	
HEC	• Cell delineation (ITU-T I.432, RA-NWT-001112)
Cell Descrambling	Select on/off
Header Correction	Select on/off
	 Correction On: Single-bit errors are corrected and error-free cells are accepted
	Correction Off: All cells are accepted
Overflow Indication	Drop overflow (DOVL) alarm measurement and front panel indication
Idle / Unassigned Drop control	Default: cells not passed to CPP

Output Filters

Number of filters	• 6
Pattern match fields for filter	 GFC (UNI mode only): single value or "any". VPI: single value or "any". VCI: single value or "any". PTI: bit mask and bit value (3 bits) or "any"
Default Values	 All VPI = "any", VCI = "any" Signalling channel: VPI = 0, VCI = 5 OAM F4 Segment: VPI = "any", VCI = 3 OAM F4 End-to-End: VPI = "any", VCI = 4 OAM F5 Segment: VPI = "any", VCI = "any", PTI = 100 OAM F5 End-to-End: VPI = "any", VCI = "any", PTI = 101

Low Speed Cell Bus Control

Bandwidth

- Cells from the 155 Mb/s cell bus can be inserted into an ATM bandwidth of 149.76 Mb/s
- Cells from the link can be passed to the cell bus at rates of up to 149.76 Mb/s to modules placed to the left of the Agilent E1618A.

Measurements

ATM Real-Time Measurements

Total Received Cell • Total utilized cell bandwidth (C) Bandwidth		
Total Received Cell Count	Total received cell count (C)	
Bad Headers	HEC Errors (C, R)	
	 Defined as 2 or more bit errors with Header Correction On 	
	 Defined as 1 or more bit errors with Header Correction Off 	
Corrected Headers	Correctable HEC Errors (single-bit errors) (C, R) Only valid with Header Correction On	
LOCS	Loss of Cell Synchronization status (S)	
Inserted Cell BW	Mean bandwidth of cells inserted from add bus.	
Inserted Cell Count	Count of cells inserted from add bus (C).	

ATM Receive Filter Measurements

	Number of Filters	•	6
	Received Average Cell Bandwidth per filter	•	Bandwidth averaged over integration period.
	Received Peak Cell Bandwidth per filter	•	Greatest bandwidth received within a 100mS period.
-	Receive Cell Count per filter	•	Cumulative cell count over the integration period.
	Drop Cell Count	•	Actual drop cell count accumulated over the integration period.
	Drop Cell Bandwidth	•	Actual drop cell bandwidth averaged over the integration period.
-	Drop Overflow Errored Seconds	•	Number of seconds during the integration period when there was at least one cell lost due to the drop overflow condition.

Dynamic Measurements

Total band	dwidth passed
to cell bus	(to CPP)

- The bandwidth of ATM cells based on the BSTS cell bus (less than 149.76 Mb/s)
- Channel Average Cell Bandwidth
- Selected channel cell bandwidth averaged over last complete 1 second period.
- Up to 6 channels simultaneously

Electrical Specification

Input and Output

Optical Receiver

Input	 1310 nm single mode PIN based receiver 		
	 Complies with Telcordia GR-253-CORE (Issue 1, Dec. 94) and ITU-T G.957 (07/95) intermediate reach specifications 		
Sensitivity	• -28 dBm (min)		
Connector	• SC (standard)		
	 FC-PC and ST adaptors available 		

Optical Transmitter

Output	• 1310 nm Class 1 single mode laser
σατρατ	Complies with Telcordia GR-253-CORE (Issue 1,
	Dec. 94) and ITU-T G.957 (07/95) intermediate reach specifications
	• Optical 10 dB attenuators available (multimode).
Average Output Power	● -8.0 dBm (max)
Connector	• SC (standard)
	 FC-PC and ST adaptors available
Safety	Complies with IEC 825/CDRH Class 1
Operation	Laser can be switched on/off
	 Default condition at power on: Off

Operating Modes

Full Duplex (Terminal Mode)	Independent transmitter and receiver operation
Receive Loopback (Far End Loopback)	Received signal is retransmitted without modification Provides a passive monitor function
Transmit Loopback (Near End Loopback)	Transmit signal is electrically looped back to the receiver Enables monitoring of generated traffic

Transmit Clock Selection

Internal Clock	Stratum 3
Timing Reference Module	• E1679A
Recovered Clock	• Includes jitter reduction
External Clock Input (front panel)	SMB connector

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Backplane Trigger Lines	• ECLO/1	AIS-P	Path AIS (Level)	
Electrical Interface		RDI-P	Path RDI (Level)	
Reference Clock	Connector Type: SMB bulkhead receptacle input	LOS	Loss of Signal (Level)	
	Specification: 0 dBm (nominal) terminated in	LOP	Loss of Pointer (Level)	
	50 ohm to ground inputSignal: Clock at 622.08 MHz (nominal)	00F	Out of Frame (Level)	
	• Duty Cycle: 50+/–5%	LOF	Loss of Frame (Level)	
External Trigger Tx	 Connector Type: SMB bulkhead receptacle Output Levels: TTL source 	Rx Frame Sync	SONET/SDH frame synchronization pulse (Pulse)	
	Output Impedance: 50 ohm	LOCS	Loss of Cell synchronization (Level)	
External Trigger Rx	Connector Type: SMB bulkhead receptacle		 Minimum asserted period of 125 ms (synchronized to frame) 	
	Output Levels: TTL sourceOutput Impedance: 50 ohm	Match cell received	Match cell received (Pulse)	
Serial Clock and Data	Connector Type: SMB bulkhead receptacle	Drop Overflow	Buffer overflow condition (Pulse)	
Inputs/Outputs	Input/Output Levels: 10E Series ECL			
	 Output: 50 ohm termination to -2 V required Input: 50 ohm termination to -2 V provided 	Mechanical Specifications		
	 Compatible with existing Agilent Broadband Series Test System and Series 90 modules 	VXI Module		
	ocites rest dystem and ocites do modules	Size	• 1 slot C-size VXI card	
Triggers		Weight	• 2.0 kg nominal	
Nominal Pulse Width	• 25 ns	Power Dissipation	• 50 Watts (max)	
Trigger Types	Level: Level active for the event	Backplane Connectors	• P1, P2	
	Pulse: Pulsed on the event	Addressing	Logical and servant addressing	
Transmit Triggers		Front Panel LED Indica	ators	
AIS-L	Line AIS (Level)	Failed	Red during self-test	
RDI-L	Line RDI (Level)	i uncu	Off upon successful completion of self-test	
AIS-P	Path AIS (Level)	Error	Red upon detection of software error	
RDI-P	Path RDI (Level)		 Application software is notified and responds as appropriate 	
Laser On/Off	Transmit laser state (Level)	Access	Green during VME bus access by another device	
BIP Insert	Single BIP insertion (Section, Line, and Path) (Level)	Gating	Green during each statistical measurement period Off for 0.1 second per measurement period	
Tx Frame Sync	SONET/SDH frame synchronization pulse (Pulse)	Signal	Green during detection of valid receive signal	
Cell inserted	Cell inserted from add bus (Pulse).	LOF	Yellow during LOF or OOF condition	
Pagaina Triggora		AIS	Yellow during LOF or OOF condition Yellow during L-AIS or P-AIS alarm	
Receive Triggers	• Line ALS (Level)			
AIS-L	Line AIS (Level) Line BDI (Level)	BIP	 Yellow during detection of SBIP, LBIP or PBIP error 	
RDI-L	Line RDI (Level)	-		

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LOCS	 Yellow during Loss of Cell Synchronization (unable to delineate cells)
Ref Clk	 Yellow during detection of valid clock signal with Tx External Clock selected
Laser	Red while transmit laser source is enabled

Environmental Operating Conditions

Operating Temperature	 0°C to 45°C Jitter transfer specification maintained over the range 10°C to 45°C
Storage Temperature	• -40°C to 70°C
Humidity	• 0% to 95% relative humidity from 25°C to 40°C

Regulatory Compliance

Environmental/Regulatory Testing

This module conforms to the following environmental/regulatory tests:

- EN55011 Limits and methods of measurement of electromagnetic disturbance characteristics of industrial, scientific, and medical radio frequency equipment
- CSA22.2 No. 1010.1, EN61010-1, UL3111-1 Safety requirements for electrical equipment for measurement, control, and laboratory use
- IEC801-2 Electromagnetic Compatibility for Industrial process measurement and control equipment, Part 2: Electrostatic discharge requirements
- IEC801-3 Electromagnetic Compatibility for Industrial process measurement and control equipment, Part 3: Radiated electromagnetic field requirements
- IEC801-4 Electromagnetic Compatibility for Industrial process measurement and control equipment, Part 4: Electrical fast transient/burst requirements
- 21CFR, IEC825 FDA Laser Classification, European Laser Safety
- ETM757 Temperature Tests, ETM758 Humidity Tests
- ETM754 Thermal Profile Mapping, ETM761 Altitude Tests

Shock and Vibration

ETM759 Vibration	 Operational Functional: Class B2 Random Vibration Survival, Swept Sine: Class B2 Swept Sine 		
	 Survival, Random Vibration: Class B2 		
EMT760 Shock	• End Use Handling: Class B2		
	• Transportation Environment: Type 1		
ETM Package	Vibration: Swept Sine Type 1		
Performance	Random Vibration		
	Impact: Type 1		

Applicable Standards

ATM Cells	 ITU-T I.361 B-ISDN ATM layer specification 1995 HEC delineation: ITU-T I.432, TA-NWT-001112 	
SONET/SDH Frames	SONET STS-12c: ANSI T1.105 and Telcordia GR-253-CORE (Issue 1, Dec. 94)	
	 SDH STM-4c: ITU-T Re G.708/G.709, 1993 	

Optical Transmitter and Receiver

- Telcordia GR-253-CORE (Issue 1, Dec. 94) and ITU-T G.957 (07/95) specifications for intermediate reach systems at 1310 nm
- · If any conflict between the two standards exists, then ANSI T1.105.1996 is used
- Safety: IEC 825/CDRH Class 1



Acronyms		OAM	Operations, Administration and Maintenance
AAL	ATM Adaptation Layer	OC-12c	Optical Carrier Level 12 Signal Concatenated
ABR	Available Bit Rate	00F	Out of Frame
AIS	Alarm Indication Signal	OPT	E6270A OAM Protocol Tester
ANSI	American National Standards Institute	PDU	Protocol Data Unit
API	Application Programming Interface	РОН	Path Overhead
ASP	E1609A 0-622 Mb/s ATM Stream Processor	PTI	Payload Type Identifier
ATM	Asynchronous Transfer Mode	PVC	Permanent Virtual Circuit
BIP	Bit Interleaved Parity	QoS	Quality of Service
BISDN	Broadband Integrated Services Digital Network	RDI	Remote Defect Indication
BSTS	E4200/E4210 Broadband Series Test System	REI	Remote Error Indication
BW	Bandwidth	Rx	Receive
CBR	Constant Bit Rate	SDH	Synchronous Digital Hierarchy
CLP	Cell Loss Priority	SMB	Subminiature Type B
CPP	E4209B Cell Protocol Processor	SONET	Synchronous Optical Network
CRC	Cyclic Redundancy Check	SPE	Synchronous Payload Envelope
DOVL	Drop Overflow	ST	Segment Type
ECL	Emitter Controlled Logic	STM	Synchronous Transfer Mode
FIF0	First In First Out	STM-4c	Synchronous Transfer Mode Level 4 Signal Concatenated
GCRA	Generic Cell Rate Algorithm	SVC	Switched Virtual Circuit
GFC	Generic Flow Control	Tcl	Tool Command Language
HEC	Header Error Check	Tk	Graphical User Interface Toolkit for Tcl
ITU-T	International	ТОН	Transport Overhead
	Telecommunication Union -	TTL	Transistor-Transistor Logic
	Telecommunication Standardization Sector	Тх	Transmit
LANE	Local Area Network Emulation	UNI	User Network Interface
LED	Light Emitting Diode	VBR	Variable Bit Rate
LOCS	Loss of Cell Synchronization	VC	Virtual Channel
LOF	Loss of Frame	VCI	Virtual Channel Identifier
LOP	Loss of Pointer	VME	Versa Module Eurocard
LOS	Loss of Signal	VP	Virtual Path
MS	Meta Signalling	VPI	Virtual Path Identifier
NDF	New Data Flag	UBR	Unspecified Bit Rate
NNI	Network Node Interface and Network-to-Network		

Interface



Agilent Technologies Broadband Series Test System

The Agilent Technologies BSTS is the industry-standard ATM/BISDN test system for R&D engineering, product development, field trials and QA testing. The latest leading edge, innovative solutions help you lead the fast-packet revolution and reshape tomorrow's networks. It offers a wide range of applications:

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www.Agilent.com/comms/BSTS

United States:

Agilent Technologies Test and Measurement Call Center P.O. Box 4026 Englewood, CO 80155-4026 1-800-452-4844

Canada:

Agilent Technologies Canada Inc. 5150 Spectrum Way Mississauga, Ontario L4W 5G1 1-877-894-4414

Europe:

Agilent Technologies European Marketing Organisation P.O. Box 999 1180 AZ Amstelveen The Netherlands (31 20) 547-9999

Japan:

Agilent Technologies Japan Ltd. Measurement Assistance Center 9-1, Takakura-Cho, Hachioji-Shi, Tokyo 192-8510, Japan Tel: (81) 426-56-7832 Fax: (81) 426-56-7840

Latin America:

Agilent Technologies Latin American Region Headquarters 5200 Blue Lagoon Drive, Suite #950 Miami, Florida 33126 U.S.A.

Tel: (305) 267-4245 Fax: (305) 267-4286

Fax: (852) 2506-9233

Asia Pacific:

Agilent Technologies 19/F, Cityplaza One, 1111 King's Road, Taikoo Shing, Hong Kong, SAR Tel: (852) 2599-7889

Australia/New Zealand:

Agilent Technologies Australia Pty Ltd 347 Burwood Highway Forest Hill, Victoria 3131 Tel: 1-800-629-485 (Australia) Fax: (61-3) 9272-0749 Tel: 0-800-738-378 (New Zealand)

Fax: (64-4) 802-6881

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